

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination MIYACHI ET AL.	
		Examiner Sean P. Cullen, Ph.D.	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0061446	05-2002	Gan et al.	429/231.8
*	B US-2003/0054249	03-2003	Yamamoto et al.	429/231.1
C	US-			
D	US-			
E	US-			
F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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